

Application/Control No.	Applicant(s)/Patent under Reexamination
10/628,500	MIYAZAWA ET AL.
Examiner	Art Unit
Khiem D. Nguyen	2823

	SEARCHED				
Class	Subclass	Date	Examiner		
438	379	11/22/2006	K.N.		
438	171	11/22/2006	K.N.		
438	190	11/22/2006	K.N.		
438	210	11/22/2006	K.N.		
438	238	11/22/2006	K.N.		
438	239	11/22/2006	K.N.		
438	381	11/22/2006	K.N.		
361	. 56	11/22/2006	K.N.		
361	277	11/22/2006	K.N.		
361	58	11/22/2006	K.N.		
361	271	11/22/2006	K.N.		
257	312	11/22/2006	K.N.		
257	595	11/22/2006	K.N.		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		,			
		-			
search (US	terference S-PGPUB), ch history.	11/22/2006	K.N.		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST text search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	11/16/2006	K.N.
Consulted Primary Examiner (Mr. Jackson Stephen W., AU 2836).	11/22/2006	K.N.
·		